



High Speed AFM-Raman Optimized for Nanoscale Chemical Imaging: Making TERS An Accessible Technique

LIVE WEBINAR: November 12, 2013 at 8:00 am PST / 11:00 am EST
Register Free at www.spectroscopyonline.com/AFMRaman

EVENT OVERVIEW:

Scanning Probe Microscopy (SPM) and in particular Atomic Force Microscopy (AFM) allow imaging of physical properties at the nanoscale, while vibrational spectroscopy, especially Raman spectroscopy, enables chemical imaging with diffraction limited resolution. Horiba and AIST-NT are now able to demonstrate that AFM-Raman imaging can be performed routinely, simultaneously, and without compromises, bringing TERS within reach of most researchers.

In this seminar, we will discuss:

- The Integration of SPM and optical spectroscopy without compromises.
- How ultrafast and simultaneous SPM and hyperspectral imaging enables correlation of morphological and chemical properties as well as selection of nanoparticles for individual characterization, isolation or directed synthesis.

Key Learning Objectives:

- Understand the key functionalities that enable SPM and optical spectroscopy to be performed simultaneously with high throughput.
- Understand the different requirements of tip enhanced Raman imaging versus co-localized (same spot) measurements.
- Understand how today's solutions will save you time, relieve frustration, and will let you approach subdiffraction limit chemical imaging with confidence.

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Advanced Integrated Scanning Tools for Nano Technology

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Solutions for Materials Analysis

Presenters

Emmanuel Leroy
AFM-Raman Product Manager
at HORIBA Scientific

Andrey Krayev
Chief Technology Officer at
AIST-NT

Moderator

Laura Bush
Editorial Director,
Spectroscopy

Who Should Attend:

- Academic and industrial researchers working with common Raman active nanomaterials such as carbon nanotubes, graphene, MoS₂, semiconductor films and devices, and designing nanoparticles or coatings
- Lab managers and user facility managers looking for multimodal imaging instrumentation combining many techniques into one platform

For questions, contact Kristen Moore
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